•	Application No.	Applicant(s)	
Notice of Allowshills	09/380,410	JENAU ET AL.	
Notice of Allowability	Examiner	Art Unit	
	Anjan K Deb	2858	
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication GHTS. This application is subject to	olication. If not include will be mailed in due	ed course. THIS
 This communication is responsive to <u>amendment filed 6-12</u> The allowed claim(s) is/are <u>1-21 and 25</u>. The drawings filed on are accepted by the Examine Acknowledgment is made of a claim for foreign priority und a) All b) Some* c) None of the: 	r.		
 Certified copies of the priority documents have 	been received.		
2. Certified copies of the priority documents have	been received in Application No	·	
3. Copies of the certified copies of the priority doc	cuments have been received in this r	national stage applica	tion from the
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
 Acknowledgment is made of a claim for domestic priority ur The translation of the foreign language provisional a 		onal application).	
6. Acknowledgment is made of a claim for domestic priority ur	• •		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of below. Failure to timely comply will result in ABANDONMENT of to a SUBSTITUTE OATH OR DECLARATION must be subminFORMAL PATENT APPLICATION (PTO-152) which gives reas	this application. THIS THREE-MON itted. Note the attached EXAMINER'	TH PERIOD IS NOT S AMENDMENT or N	EXTENDABLE.
 8. ☐ CORRECTED DRAWINGS must be submitted. (a) ☐ including changes required by the Notice of Draftspers 1) ☐ hereto or 2) ☐ to Paper No. 8. (b) ☐ including changes required by the proposed drawing of the including changes required by the attached Examiner's 	orrection filed, which has be	en approved by the E	
(e, Z more ing changes required by the attached Entire in		mile delien or raper	10. <u>17</u> .
Identifying indicia such as the application number (see 37 CFR 1. of each sheet. The drawings should be filed as a separate paper	84(c)) should be written on the drawing with a transmittal letter addressed to t	gs in the top margin (n he Official Draftsperso	ot the back) on.
 DEPOSIT OF and/or INFORMATION about the depos attached Examiner's comment regarding REQUIREMENT FOR TI 	sit of BIOLOGICAL MATERIAL m HE DEPOSIT OF BIOLOGICAL MAT	oust be submitted. N ERIAL.	lote the
Attachment(s)			
 Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO-948) Information Disclosure Statements (PTO-1449), Paper No	2☐ Notice of Informal 4☐ Interview Summa 6☑ Examiner's Amen 8☑ Examiner's Stater 9☐ Other	ry (PTO-413), Paper idment/Comment	No
		N. Le	
	Supervi Techr	sory Patent Examin	er

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DETAILED ACTION

1. This office action is in response to amendment filed 6-12-02.

EXAMINER'S AMENDMENT

2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with attorney of record Mr. Zborovsky on 13 June 2002.

The application has been amended by replacing the abstract with the following:

Abstract

A method and device for measuring electrical voltage allow measurement under open-air conditions including high-voltage and very high voltage. Influence of temperature changes on electrical and optical parameters of the device are reduced by using light sources, at least one optical transmission path, at least one sensor element with at least one active sensor part made up of several sensor crystals and evaluation by Pockel's effect using optical activity in a crystal. Measurement light generated by a light source penetrates an active sensor, which has at least two

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sensor crystals and at least one active sensor part in the sensor element where there is a voltage drop and the polarization state of measurement light is used for measuring voltage. A sensor element can be made up of several active sensor parts and the total voltage obtained from the summation of partial voltages across sensor parts by an evaluation unit having a function for performing integration. Several sensor elements may be combined and transmitted optical waves are converted to electrical signals for evaluation of voltage.

Drawings

In Figure 1 and 2 a -- Prior Art-- legend has been added. See MPEP § 608.02(g).

Claims

In claim 1, lines 16-17 "the scaling" has been changed to -scaling--.

In claim 9, line 9 "the scaling" has been changed to -scaling--.

Allowable Subject Matter

3. Claims 1-21,25 are allowed.

Reasons for Allowance

4. The following is an examiner's statement of reasons for allowance:

Claims 1-8 are allowed because the prior art of record, or that encountered in searches performed by the examiner does not teach or suggest the claimed method of measuring electrical

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voltage comprising evaluation means for evaluating the polarization state of measurement light traversed through sensor crystals wherein the evaluation means is used with a component assembly for scaling and multiplying input signal by a factor generated by a function unit, its input quantity representing the difference between a reference signal and a factored output signal wherein the function unit performs integration.

Claims 9-21,25 are allowed for a device for measuring alternating electrical voltage comprising evaluation means using Pockel's effect in sensor crystals penetrated by polarized light wherein the evaluation means contain at least one component assembly for scaling by multiplying input signal by a factor generated by a function unit, its input quantity representing the difference between a reference signal and a factored output signal wherein the function unit performs integration.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

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Contact Information

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dr. Anjan K. Deb whose telephone number is (703) 308-2941. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, N. Le, can be reached at (703)-308-0750.

Any inquiry of a general nature or relating to the status of this application should be directed to the Group receptionist whose telephone numbers are (703)-308-0956 and (703)-305-4900.

Anjan K. Deb

Tel: 703-308-2941

Patent Examiner

Anjan In Dab

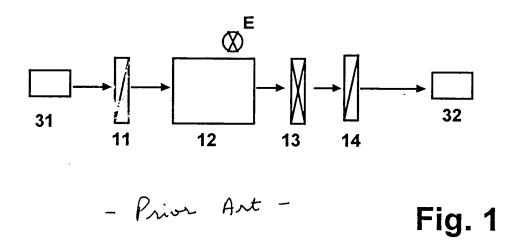
Fax: 703-746-4466

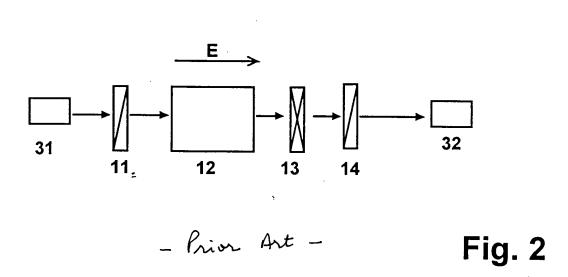
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E-mail: anjan.deb@uspto.gov

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